Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,371	CHAN ET AL.
Examiner	Art Unit
Linh V. Nguyen	2819

SEARCHED			
Class	Subclass	Date	Examiner
330	277,296, 285 286,290	12/19/2007	LN

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	DATE	EXMR
East searched-see printout	12/19/2007	LN